

IN THE SPECIFICATION

Page 1, the second full paragraph, lines 12 to 17,
replace the paragraph with:

Thus, the sampling apparatus of the present invention is used, for instance, for collecting a dust or foreign substance substances attached to the surface of silicon wafers (semiconductor wafers) used for producing integrated circuits (IC) (IC's) and others other devices. For the purpose of the present invention, the term "attached" includes the meaning meanings of "very weakly adhered" and "settled".

Pages 1 and 2, the paragraph bridging these pages from page 1, line 26 to page 2, line 9, replace the bridging paragraph with:

Conventional sampling apparatuses in this field are constructed with their optical microscope portion and sampling portion being integrated. When the conventional apparatuses were are used and the surface of a semiconductor wafer was is observed with the optical microscope portion to find a dust or foreign substance, a sampling needle of the sampling portion is used to be which is moved by operating a joy stick or the like to bring the tip of the sampling needle close to or to make the tip of the needle contact with the dust or foreign

substance (sample for microscopic analysis) thereby to catch the dust or foreign substance by the tip of the sampling needle.

Page 2, the first full paragraph, lines 10 to 16, replace the paragraph with:

However, conventional sampling apparatuses require skill of a person who practices the sampling, because when conventional apparatuses are used, sampling of a dust or foreign substance (sample for microscopic analysis) is performed by moving a sampling needle while observing the dust or foreign substance through a microscope after the person ~~discovered~~ discovers the dust or foreign substance on the surface of a semiconductor wafer.

Page 2, the second full paragraph, lines 17 to 21, replace the paragraph with:

Besides, it ~~was~~ is impossible to ~~install~~ mount only a sampling portion of conventional sampling apparatuses to other ordinary microscopes and conduct a sampling since conventional sampling apparatuses are constructed with their optical microscope portion and a sampling portion being integrated.

Page 2, the third full paragraph, lines 22 to 25, replace the paragraph with:

Accordingly, conventional sampling apparatuses ~~were~~ are expensive, and it ~~was~~ is impossible for people who ~~did~~ do not have a sampling apparatus to readily conduct a sampling even when they ~~had~~ have an optical microscope.

Pages 2 and 3, the paragraph bridging these pages from page 2, line 27 to page 3, line 1, replace the bridging paragraph with:

~~Considering the situations described above,~~ The objects of the present invention are:

Page 3, the first full paragraph, lines 2 to 3, replace the paragraph with:

{001} to make it possible to readily collect a minute sample for microscopic analysis,

Page 3, the second full paragraph, lines 4 to 6, replace the paragraph with:

{002} to provide a sampling apparatus having a simple structure and being low in its cost, and to provide a sampling method in which sampling operations are simple, and

Page 3, the third full paragraph, lines 7 to 8, replace the paragraph with:

{003} to provide a sampling apparatus which can be used by detachably install installing it ~~to~~ on an ordinary microscope.

Page 3, the fifth full paragraph, lines 12 to 13, replace the paragraph with:

{A01} a frame fixed at a prescribed position relative to the object lens of an optical microscope.

Page 3, the sixth full paragraph, lines 14 to 16, replace the paragraph with:

{A02} a moving member supported with the fixed frame so as to be reciprocatably movable between a sampling position and a waiting position,-

Page 3, the seventh full paragraph, lines 17 to 18, replace the paragraph with:

{A03} a member for holding the moving member at the waiting position,

Page 3, the eighth full paragraph, lines 19 to 25,
replace the paragraph with:

(A04) a device for adjusting the position of a sampling
needle relative to the moving member so that the tip of the
sampling needle is situated at the focus position of the
object lens of the optical microscope (hereinafter, sometimes,
the words "the object lens of" are omitted for brevity) in the
state wherein the moving member was moved to the sampling
position, and

Pages 3 and 4, the paragraph bridging these pages from
page 3, line 26 to page 4, line 3, replace the bridging
paragraph with:

(A05) means for fixing the sampling needle to the moving
member in the state wherein the position of the sampling
needle relative to the moving member ~~was~~ is adjusted so that
the tip of the sampling needle is situated at the focus
position of the optical microscope.

Page 4, the second full paragraph, lines 7 to 11, replace
the paragraph with:

(B01) a sample moving step in which the surface to which
a sample to be inspected or analyzed is attached is moved,

preferably together with the sample stage which supports the surface, so that the sample is moved to the focus position of an optical microscope,

Page 4, the third full paragraph, lines 12 to 18, replace the paragraph with:

{B02} a needle moving step in which a moving member, which supports a sampling needle and is moved integratedly with the sampling needle, is moved from a waiting position where the position of the tip of the sampling needle is apart from the focus position of an optical microscope to a sampling position where the tip of the sampling needle is situated at the focus position of the optical microscope, and

Page 4, the fourth full paragraph, lines 19 to 21, replace the paragraph with:

{B03} a sampling step in which a sample is caught on the tip of the sampling needle and taken away from the surface to collect the sample

Pages 6 and 7, the paragraph bridging these pages from page 6, line 26 to page 7, line 4, replace the bridging paragraph with:

In these Figures, M designates an optical microscope, 1: a flame to be fixed, 15: a moving member, 17: a member (a compression spring) for holding a moving member at a waiting position, 23: a sampling needle, 24: means for fixing a sampling needle (a fixing screw), and ~~11e, 21, 22~~: an apparatus for 11e: a hole and 21 and 22: a hole or members used for adjusting needle position.

Page 7, the third full paragraph, lines 21 to 26, replace the paragraph with:

The Position of a sampling needle (23) relative to the moving member (15) can be adjusted with a device ~~11e, 21, 22~~ used for adjusting a needle position a member 21 inserted in hole 11e and member 22 so that the tip of the sampling needle (23) is situated at the focus position of the optical microscope (M) in the state wherein the moving member (15) was is moved to a sampling position.

Pages 7 and 8, the paragraph bridging these pages from page 7, line 27 to page 8, line 5, replace the bridging paragraph with:

Means (24) used for fixing a sampling needle fixes the sampling needle (23) to the moving member (15) in the state wherein the position of the sampling needle (23) relative to the moving member (15) ~~was~~ is adjusted so that the tip of the sampling needle (23) is situated at the focus position of the optical microscope (M).

Page 8, the first full paragraph, lines 6 to 18, replace the paragraph with:

After the surface of such a member as a semiconductor wafer to which surface a sample is attached ~~was~~ is moved to the level of the focus position of an optical microscope (M) by moving a sample stage (not shown in the Figures) of the optical microscope (M) ~~to~~ in the direction of a Z axis in the state wherein the moving member (15) ~~was~~ is held at a waiting position, a search is conducted for a sample such as a dust or foreign substance by moving the sample stage (not shown in Figures) within a plain surface XY. After the sample ~~was~~ is moved to the focus position, the sample can be caught with the tip of the sampling needle (23) by moving the moving member

(15) from a waiting position to a sampling position so that the tip of the sampling needle (23) is moved to the focus position.

Page 8, the second full paragraph, lines 20 to 26, replace the paragraph with:

(A06) a member (17) for holding the moving member (15) at a waiting position may be composed of an elastic member which acts on the moving member (15) so as to hold the member always at a waiting position, and to make the movement of the moving member (15) to a sampling position possible at the time when external force was applied to the moving member (15) so as to move the member to the sampling position.

Page 9, the second full paragraph, lines 14 to 16, replace the paragraph with:

(A07) a fixed frame may be constructed so as to be attachable to and detachable from a mirror cylinder which supports the object lens of an optical microscope (M).

Page 10, the first full paragraph, lines 6 to 10, replace the paragraph with:

{B01} a sample moving step in which preferably both of the surface to which a sample to be inspected or analyzed is attached and the sample stage which supports the surface are moved so that the sample is moved to the focus position of an optical microscope (M),

Page 10, the second full paragraph, lines 11 to 18,
replace the paragraph with:

{B02} a needle moving step in which a moving member (15), which supports a sampling needle (23) and is moved integratedly with the sampling needle (23), is moved from a waiting position where the position of the tip of the sampling needle (23) is apart from the focus position of an optical microscope (M) to a sampling position where the tip of the sampling needle (23) is situated at the focus position of the optical microscope (M), and

Page 10, the third full paragraph, lines 19 to 24,
replace the paragraph with:

{B03} a sampling step in which a sample caught on the tip of the sampling needle (23) is taken away from the surface to which the sample is attached, and then collected.

Pages 13 and 14, the paragraph bridging these pages from page 13, line 26 to page 14, line 5, replace the bridging paragraph with:

In Figs. 1A to 1C, side plate 7 is fixed to the right side surface of protruded portions 3a, 3a (see Fig. 2A) with screws 8, 8 (see Figs. 1A to 1C) passing through screw through-holes 7b, 7b (see Fig. 4A). This side plate 7 has blocked the right side end of U-shaped ditch 3b (see Fig. 2A), and has, together with U-shaped ditch 3b, a function of guiding the a slider 9 (~~described above~~) up and down.

Page 17, the first full paragraph, lines 3 to 15, replace the paragraph with:

In Fig. 8, needle holder 21 is composed of a cylindrical metallic rod, male screw 21a is formed on the outer circumferential surface at its base side portion (right side portion in Fig. 8) of the holder, and hole 21b for inserting a needle is formed at the tip side portion (left side portion in Fig. 8) of the holder. Cap-like operating knob 22 has been screwed into onto the male screw 21a and fixed thereto. Sampling needle 23 to be detachably inserted in the needle inserting hole 21b has insertable cylindrical (solid) column base portion 23a having a large diameter, and tip needle

portion 23b. The insertable cylindrical portion 23a is detachably inserted in the needle inserting hole 21b to equip the needle to the needle holder.

Page 19, the first full paragraph, lines 2 to 8, replace the paragraph with:

Needle position adjusting device, which can adjust the position of sampling needle 23 relative to the moving member 15, is constructed by the members ~~or parts indicated by symbols 11e, 21, and 22~~ so that the tip of sampling needle 23 is situated at the focus position of the object lens of optical microscope M in the state wherein the moving member 15 was moved to a sampling position member 21 is inserted in hole 11e.

Page 22, the second full paragraph, lines 5 to 9, replace the paragraph with:

In this state (shown in Fig. 9), when the slider fixing screw 16 was loosened, moving member 15 rises to move to a waiting position shown in Fig. 1B (position where the tip of sampling needle 23 is apart from the focus position of optical microscope M).

Pages 22 and 23, the paragraph bridging these pages from page 22, line 10 to page 23, line 1, replace the bridging paragraph with:

In this state, when a semiconductor wafer or the like (a member to which a sample such as a dust or foreign substance which is necessary to be inspected or analyzed might be attached) was supported on a sample stage (not shown in Figures) of optical microscope M, the surface of the member such as a semiconductor wafer was observed while moving the sample stage (not shown in Figures) ~~being moved~~, and then a sample such as dust or foreign substance was found at the focus position, the sample such as a dust or foreign substance can be caught with the tip of sampling needle 23 by moving the moving member 15 from a waiting position shown in Fig. 1B to the sampling position shown in Fig. 9 and contacting the tip to or bringing it near to the sample. Specifically, the sample can be caught with the tip, for example, by the action of static electricity or by thrusting the tip into the sample. Also, the sample can be caught by scooping or ladling the sample with the tip of sampling needle 23. A sample sample caught by the tip of the sampling needle 23 can be collected by raising moving member 15 to a waiting position shown in Fig. 1B.

Page 23, the second full paragraph, lines 6 to 22,
replace the paragraph with:

As will be understood from the recital of function of the sampling apparatus of Example 1 described above, when the surface of a member such as a semiconductor wafer or the like to which a sample might be attached (that is, the surface of a member to which a sample such as dust or foreign substance, which should be inspected, might be attached) supported on a sample stage (not shown in Figures) was observed through optical microscope M in the state wherein moving member 15 of sampling apparatus U was held in the waiting position shown in Fig. 1B, and the sample was found, the sample can be collected only by pushing down spring case 13 to move moving member 15 to a lower sampling position and then raising the member to a waiting position. That is, a sample such as a dust or foreign substance moved to the focus position of optical microscope M can simply be collected only by reciprocating moving member 15 at a waiting position (see Fig. 1B) between the waiting position and a sampling position (see Fig. 9).

Pages 28 and 29, the paragraph bridging these pages from page 28, line 24 to page 29, line 3, replace the bridging paragraph with:

{H01} In each of the apparatus of the Examples described above, as a member for holding a moving member at a waiting position, any member can be used so far as the member has a function of holding a moving member moved to a waiting position at the waiting position. For example, a screw which fixed a moving member at a waiting position can be used as waiting position holding member.

Page 29, the first full paragraph, lines 4 to 13, replace the paragraph with:

{H02} Whereas a fixed frame is constructed so as to be attachable to and detachable from a mirror cylinder of an optical microscope in each of the apparatus of the Examples described above, it is possible to construct the frame, to be fixed, integratedly with a mirror cylinder. An optical microscope in this case has a function as sampling apparatus from the outset. However, this optical microscope having a function as sampling apparatus is simple in its structure and can be manufactured at a low cost compared with conventional ones.

Page 29, the second full paragraph, lines 14 to 19,
replace the paragraph with:

{H03} In each of the apparatus of the Examples described above, a frame which is fixed at a prescribed position relative to the object lens of an optical microscope is not necessary to be fixed to a mirror cylinder which supports the object lens in the following cases (a) and (b), and the frame can be fixed to any member so far as the member has been fixed to the object lens:

Pages 29 and 30, the paragraph bridging these pages from page 29, line 27 to page 30, line 4, replace the bridging paragraph with:

{H04} In the apparatus of the present invention, reciprocation of moving member 15 between a waiting position and a sampling position can be performed through an automatic operation by using a driving member such as a motor or solenoid, instead of manual operation.